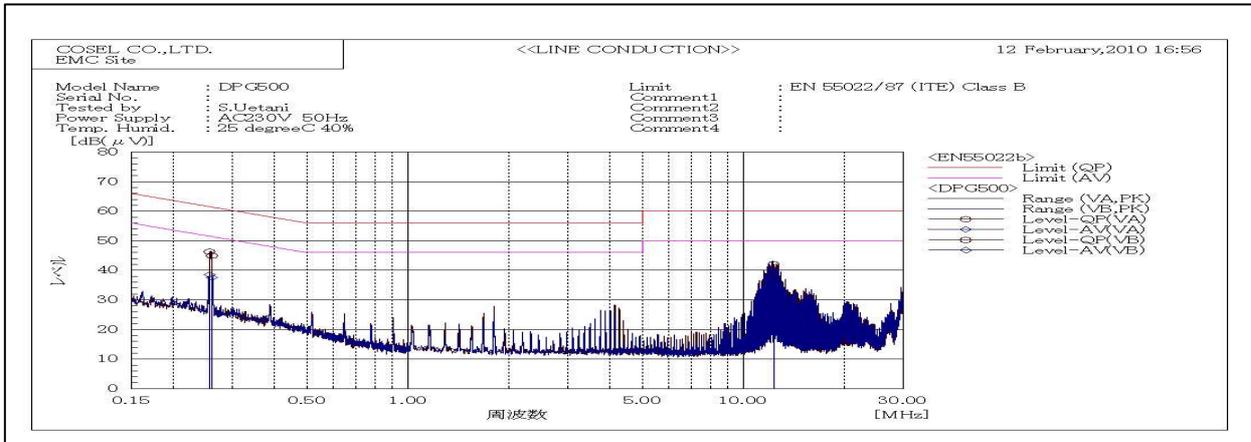
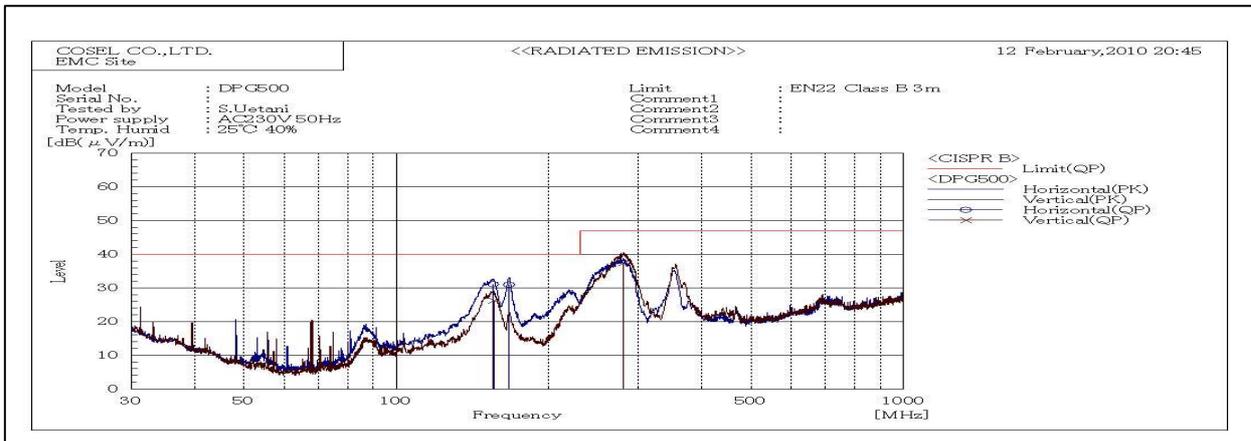


DATA SHEET		Date	09-Mar-10
Model	DPG500	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Uetani



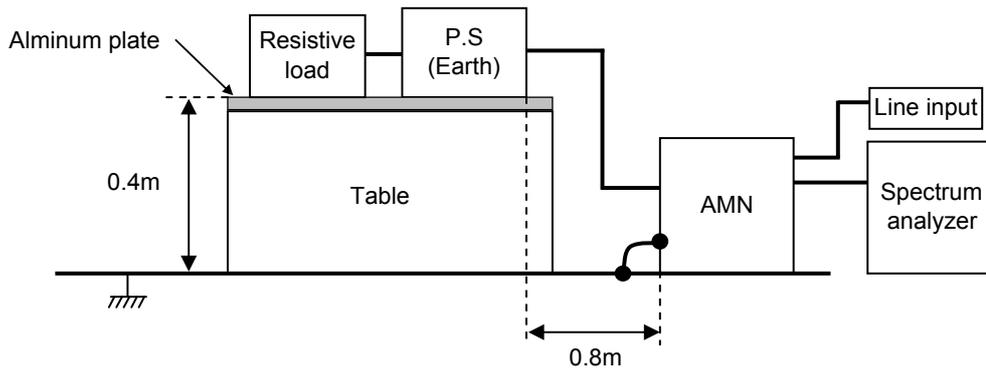
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.26059		VA	34.9	27.5	10.1	45	37.6	61.4	51.4	16.4	13.8	Pass	
0.25629		VB	36.2	28.5	10.1	46.3	38.6	61.6	51.6	15.3	13	Pass	
12.3038		VA	31.4	26.3	10.7	42.1	37	60	50	17.9	13	Pass	



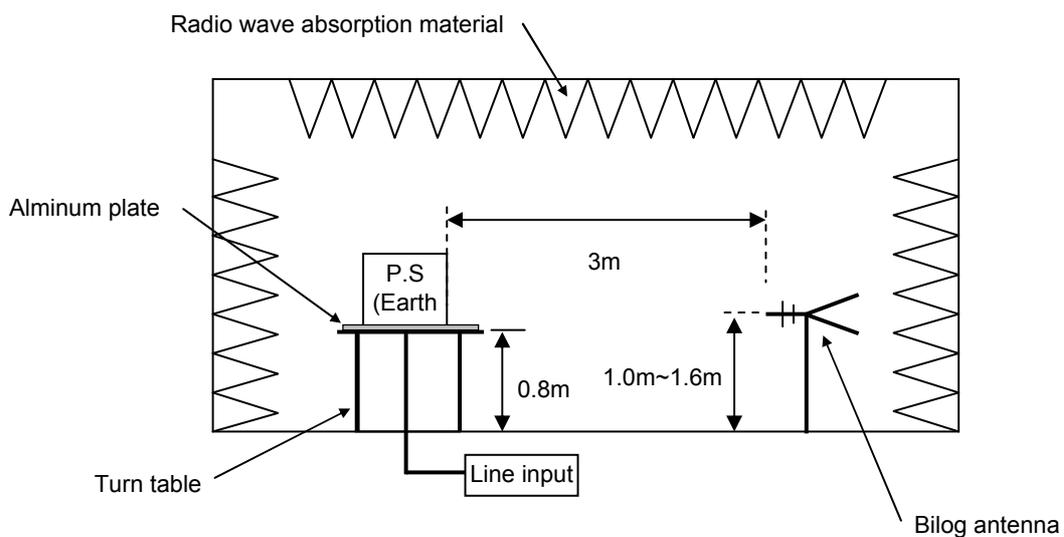
Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP						
154.932	H	Stable	51.5	-20.4		31.1	40	8.9	Pass	158	157		
155.548	V	Stable	46.7	-20.5		26.2	40	13.8	Pass	148	90		
166.67	H	Stable	52.6	-21.7		30.9	40	9.1	Pass	151	354		
280.654	V	Stable	55.2	-17.9		37.3	47	9.7	Pass	101	258		

DATA SHEET		Date	09-Mar-10
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI	Humid.	40 %RH
	Line conduction & Radiated emission	Tested by	S.Uetani

1. Line conduction



2. Radiated emission



Test: EMI

Model Name: DPG500/750

○ Photographs of Test Set-Up

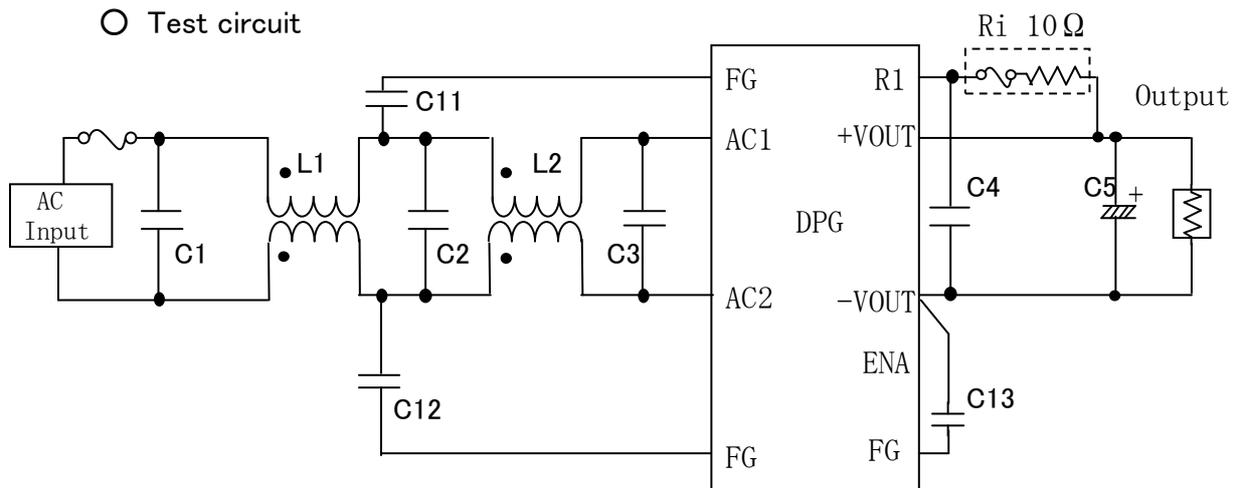
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- C1,C2,C4 : 0.68uF 250V Film Capacitor × 2
- C3 : 1.0uF 250V Film Capacitor × 2
- C5 : 560uF 450V Electrolytic Capacitor
- C11,C12,C13 : 2200pF Ceramic Capacitor
- L1,L2 : SC-15-200(NEC TOKIN)